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October 26 – 29, 2021 Virtual Event

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Integrated BMS Test with Scalable ATE

Kun Xu, Junlin Wang Advantest



Virtual • October 22-29, 2021



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* Source from Wikipedia: Electric car use by country

- As the mentioned by EV Volumes:
 - In 2020, the first wave of Covid-19 caused and unprecedented slump in car sales but also increasing support by policy makers.

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- 2021 is far from business as usual, but EV sales are back on track.



How to test BMS Device in Single ATE

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Li-xx BMS Segments for Applications



Cell x1 BMS Voltage<4.5V



Cell x2~x4 BMS Voltage<18V



Cell x3~x5 per Pack Pack x3~x4 up to 48V BMS Voltage<18V



Cell x5~x16 per Pack BMS Voltage<70V

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Cell x16~x24 per Pack Pack x4~x8 up to 400V BMS Voltage<120V



Cell x16~x24 per Pack Pack x8~xN up to 1200V BMS Voltage<120V



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Typical BMS-AFE Test Circuit



- To monitor exact voltage between Cn & Cn-1
 - Each Cn should be assigned one analog channel
- High-Res **Diff-ADCs** are core modules in AFE
 - Both DC&AC test
 - AWG is required

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Cell Balancing

- Many BMS integrate FET for cell balancing, as shown in green blocks below
- FET's Rds must be tested with high current



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Test Challenge for BMS-AFE

- The cell monitor pins are tested on HV + HC + Dynamic
- AFE tests need more analog channels



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Solution Ideas

- Add relays to switch different analog channels
 - Advantage: Can use the most appropriate testing resources
 - Disadvantage:
 - DUT board is more complex from design to maintenance
 - May be limited parallel site count based on ATE framework
- Use universal analog channels
 - Advantage: Simplify DUT board, more site count
 - Disadvantage:
 - Higher performance requirement for analog channels, such as V/I range, features...



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Test BMS-AFE with AVI64 of V93000

"General purpose" DCVI with Analog and High Voltage Digital capabilities (-40V~+80V)





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BMS-AFE Test Solution based on AVI64



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Isolate LV & HV

- BMS-AFE works with battery high voltage, but its outputs are low voltage signal, especially for digital communication with MCU
- The isolation between LV and HV is required on DUT board



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BMS-AFE Test Examples with AVI64

- VREF Trim Testing:
- 256 steps ramp wave, 1 step: ~ 0.5 mV
- Find step code on 2.5 V



- CREF Trim Testing:
- 256 steps ramp wave, 1 step: ~ 0.4x5 mV
- Find step code on 5.920V (Amplifier x5)



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Summary

- Power battery is an essential part of BEV and BMS is the brain of battery pack.
- BMS-AFE is required to monitor more and more series cells, from x16 to x24, even more.
- That means HV + HC test challenge will get higher and higher.
- Choose ATE rationally according to the characteristics of chip.
- Advantest still focuses on the newest testing technology to support Power/Analog/Controller area.



How to test BMS Device in Single ATE



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